

N-Ch and P-Ch Fast Switching MOSFETs



- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

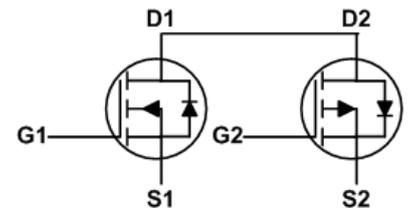
Product Summary

BVDSS	RDSON	ID
60V	23mΩ	30A
-60V	31 mΩ	-30A

Description

The XR6030 is the high performance complementary N-ch and P-ch MOSFETs with high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The XR6030 meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

TO252-4L Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-Channel	P-Channel	
V_{DS}	Drain-Source Voltage	60	-60	V
V_{GS}	Gate-Source Voltage	±20	±20	V
$I_D@T_C=25^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	30	-30	A
$I_D@T_C=100^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	13	-15	A
I_{DM}	Pulsed Drain Current ²	100	-120	A
EAS	Single Pulse Avalanche Energy ³	39	---	mJ
I_{AS}	Avalanche Current	14	---	A
$P_D@T_C=25^{\circ}C$	Total Power Dissipation ⁴	41.7	89	W
T_{STG}	Storage Temperature Range	-55 to 175	-55 to 175	°C
T_J	Operating Junction Temperature Range	-55 to 175	-55 to 175	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	---	62	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	---	3	°C/W

N-Channel Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	60	---	---	V
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =10A	---	23	32	mΩ
		V _{GS} =4.5V, I _D =5A	---	31.5	40	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.2	1.7	2.5	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =60V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =60V, V _{GS} =0V, T _J =55°C	---	---	100	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
g _{fs}	Forward Transconductance	V _{DS} =5V, I _D =10A	---	15.5	---	S
Q _g	Total Gate Charge (10V)	V _{DS} =30V, V _{GS} =10V, I _D =10A	---	22	---	nC
Q _{gs}	Gate-Source Charge		---	4.2	---	
Q _{gd}	Gate-Drain Charge		---	6.9	---	
T _{d(on)}	Turn-On Delay Time	V _{DD} =30V, V _{GS} =10V, R _G =3Ω I _D =10A	---	6.4	---	ns
T _r	Rise Time		---	15.3	---	
T _{d(off)}	Turn-Off Delay Time		---	25	---	
T _f	Fall Time		---	7.6	---	
C _{iss}	Input Capacitance	V _{DS} =30V, V _{GS} =0V, f=1MHz	---	1355	---	pF
C _{oss}	Output Capacitance		---	60	---	
C _{rss}	Reverse Transfer Capacitance		---	49	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I _S	Continuous Source Current ^{1,6}	V _G =V _D =0V, Force Current	---	---	30	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V, I _S =10A, T _J =25°C	---	---	1.2	V

Note :

1. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C
2. The EAS data shows Max. rating . The test condition is V_{DD}=25V, V_{GS}=10V, L=0.4mH, I_{AS}=14A
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
5. This value is guaranteed by design hence it is not included in the production test.

P-Channel Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-60	---	---	V
ΔBV _{DSS} /ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25C , I _D =-1mA	---	---	---	V/ C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-3A	---	31	38	mΩ
		V _{GS} =-4.5V , I _D =-2A	---	40	50	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.3	-1.7	-2.3	V
ΔV _{GS(th)}	V _{GS(th)} Temperature Coefficient		---	---	---	mV/C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-60V , V _{GS} =0V , T _J =25C	---	---	1	uA
		V _{DS} =-60V , V _{GS} =0V , T _J =55C	---	---	5	
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±20V , V _{DS} =0V	---	---	±100	nA
g _{fs}	Forward Transconductance	V _{DS} =-5V , I _D =-3A	---	---	---	S
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz	---	13	---	Ω
Q _g	Total Gate Charge (-4.5V)	V _{DS} =-30V , V _{GS} =-10V , I _D =-10A	---	13.4	---	nC
Q _{gs}	Gate-Source Charge		---	3.35	---	
Q _{gd}	Gate-Drain Charge		---	1.82	---	
T _{d(on)}	Turn-On Delay Time	V _{DD} =-30V , V _{GS} =-10V , R _G =5.0Ω , I _D =-10A	---	10	---	ns
T _r	Rise Time		---	6	---	
T _{d(off)}	Turn-Off Delay Time		---	23	---	
T _f	Fall Time		---	11	---	
C _{iss}	Input Capacitance	V _{DS} =-30V , V _{GS} =0V , f=1MHz	---	862	---	pF
C _{oss}	Output Capacitance		---	163	---	
C _{rss}	Reverse Transfer Capacitance		---	8	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I _S	Continuous Source Current ^{1,5}	V _G =V _D =0V , Force Current	---	---	-30	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25C	---	---	-1.2	V
t _{rr}	Reverse Recovery Time	I _F =-10A , di/dt=100A/μs ,	---	18	---	nS
Q _{rr}	Reverse Recovery Charge	T _J =25 C	---	27	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD}=-30V,V_{GS}=-10V,L=1mH
- 4.The power dissipation is limited by 150C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

N-Channel Typical Characteristics

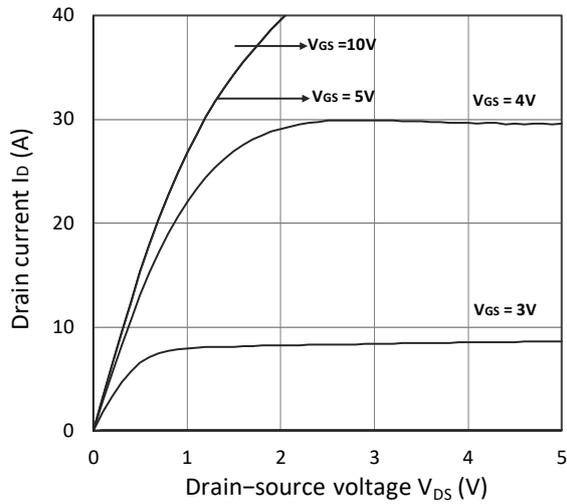


Figure 1. Output Characteristics

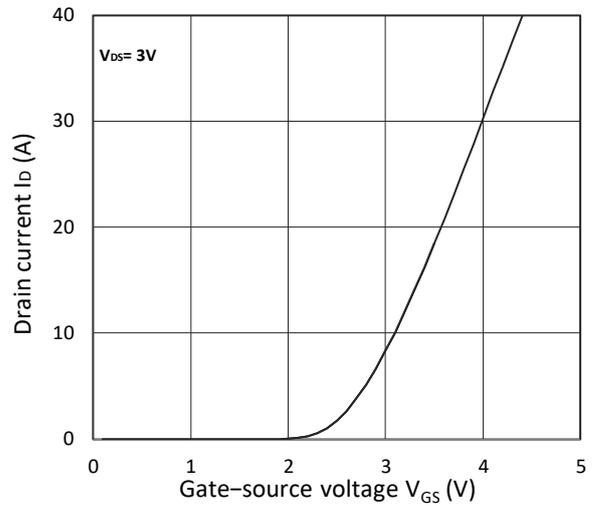


Figure 2. Transfer Characteristics

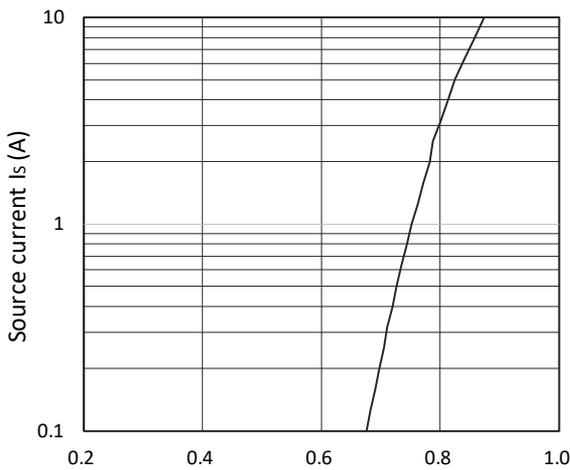


Figure 3. Forward Characteristics of Reverse

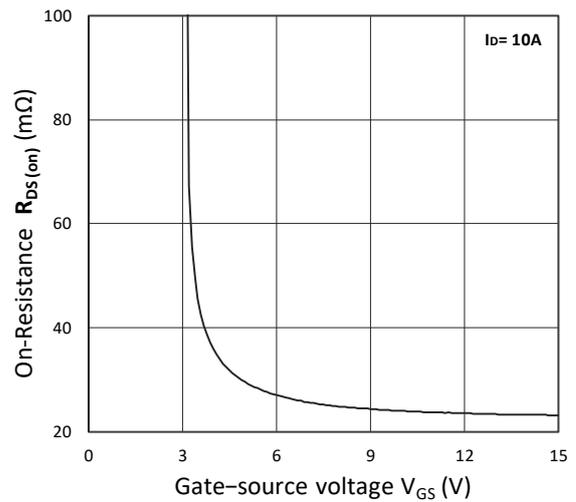


Figure 4. $R_{DS(on)}$ vs. V_{GS}

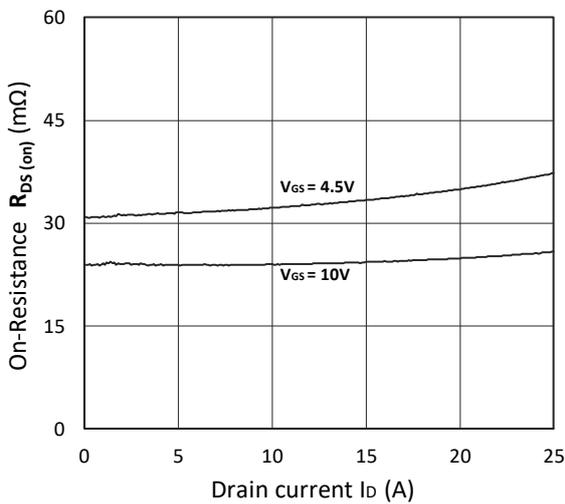


Figure 5. $R_{DS(on)}$ vs. I_D

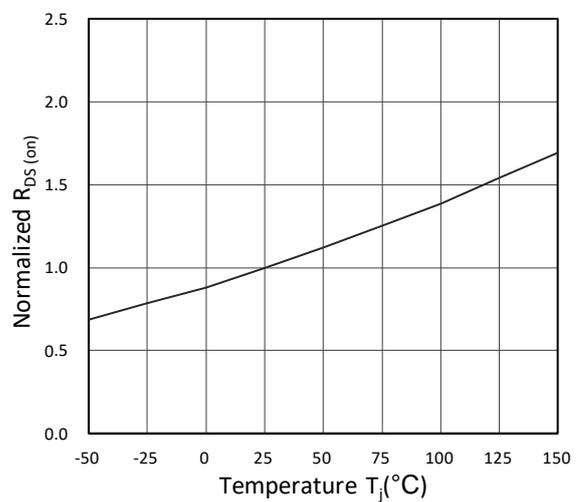


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

N-Ch and P-Ch Fast Switching MOSFETs

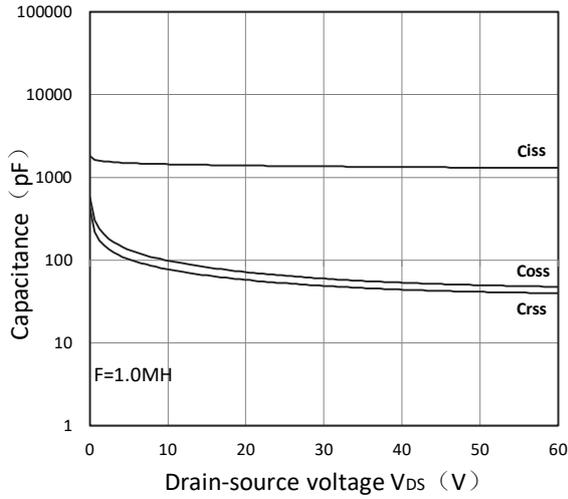


Figure 7. Capacitance Characteristics

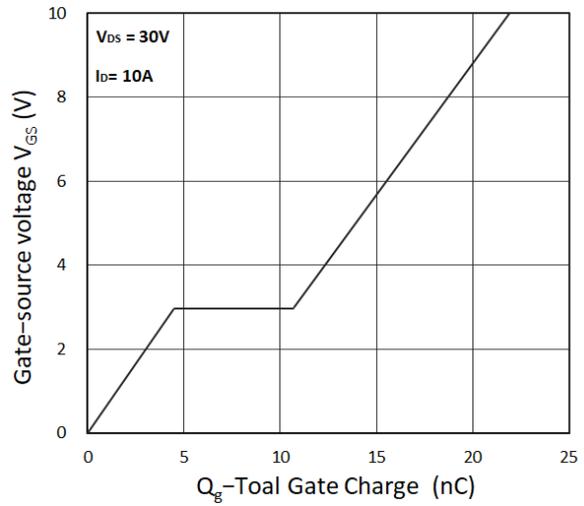


Figure 8. Gate Charge Characteristics

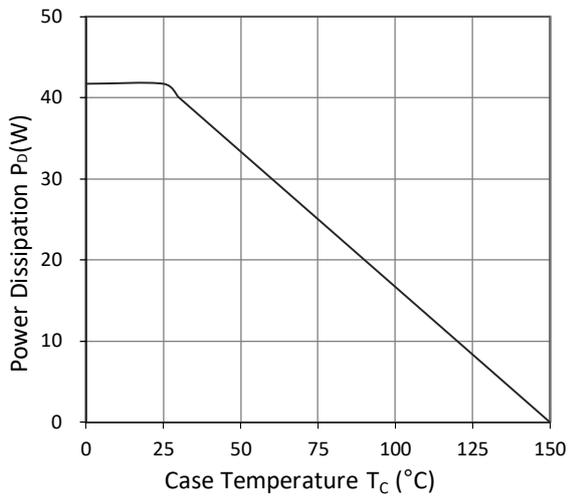


Figure 9. Power Dissipation

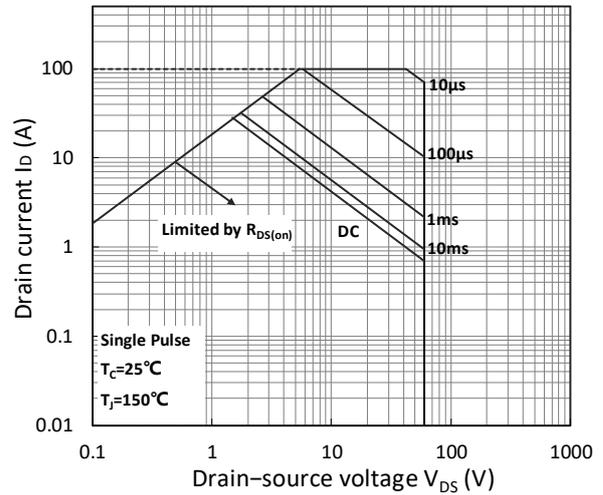


Figure 10. Safe Operating Area

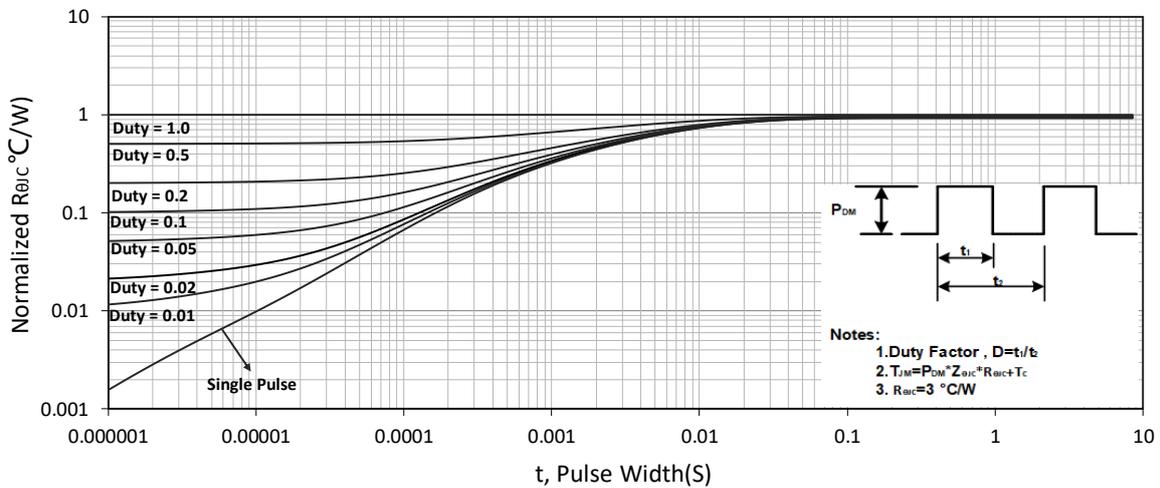
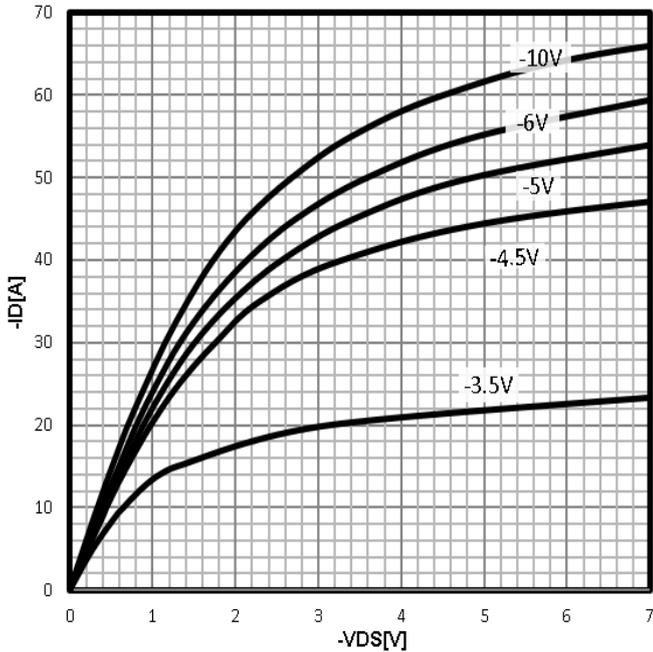


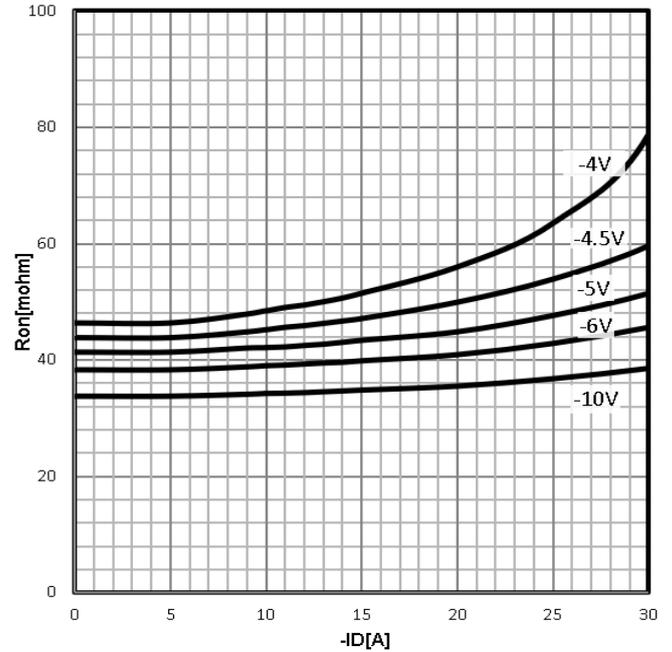
Figure 11. Normalized Maximum Transient Thermal Impedance

P-Channel Typical Characteristics

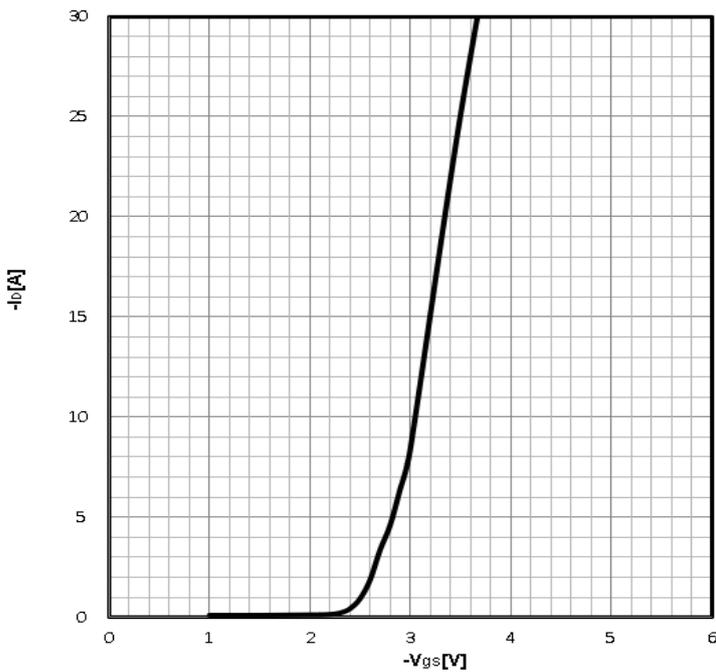
Typ. output characteristics
 $-I_D = f(-V_{DS})$



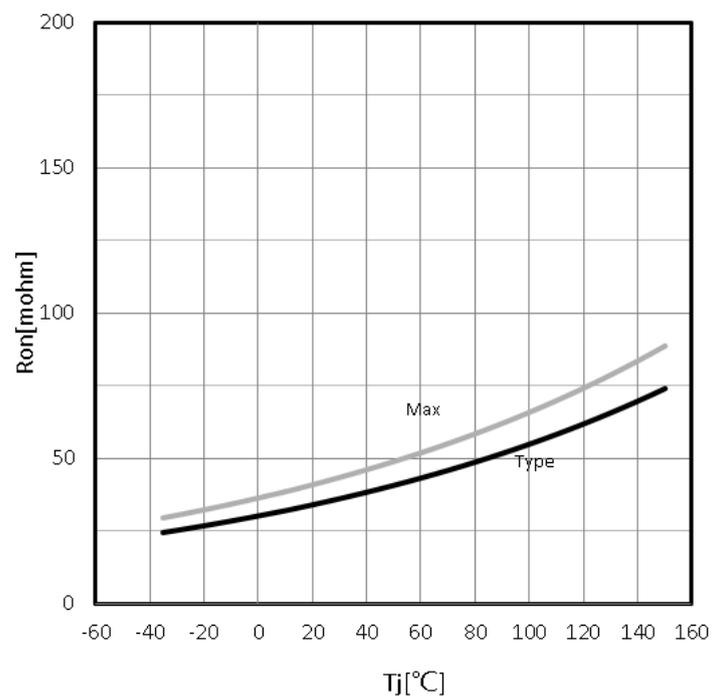
Typ. drain-source on resistance
 $R_{DS(on)} = f(-I_D)$



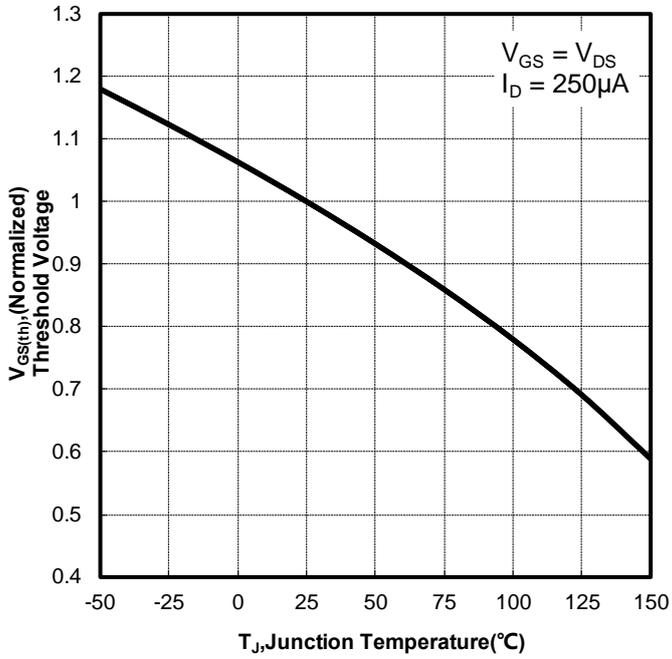
Typ. transfer characteristics
 $-I_D = f(-V_{GS})$



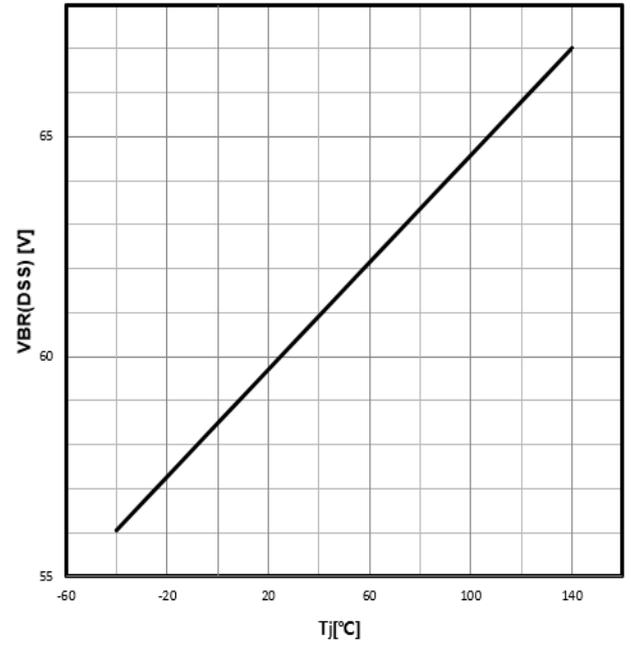
Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = -20A; V_{GS} = -10V$



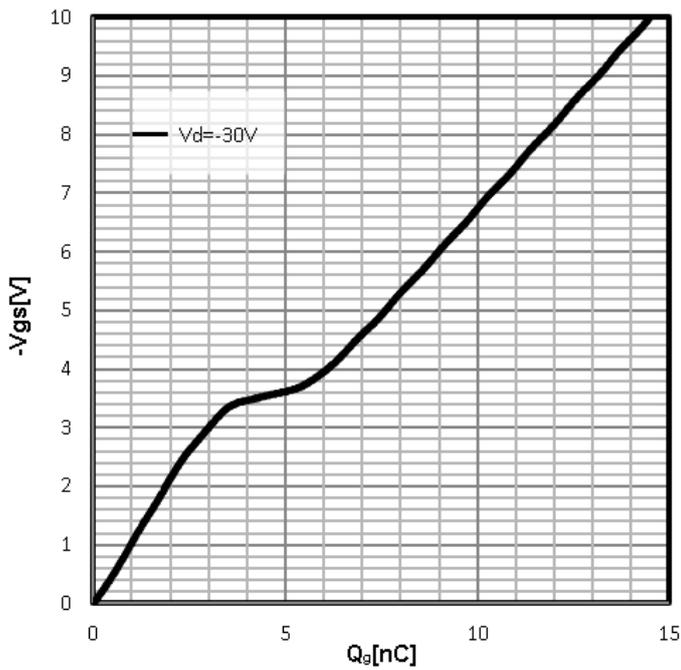
Gate Threshold Voltage
 $-V_{TH}=f(T_j); I_D=-250\mu A$



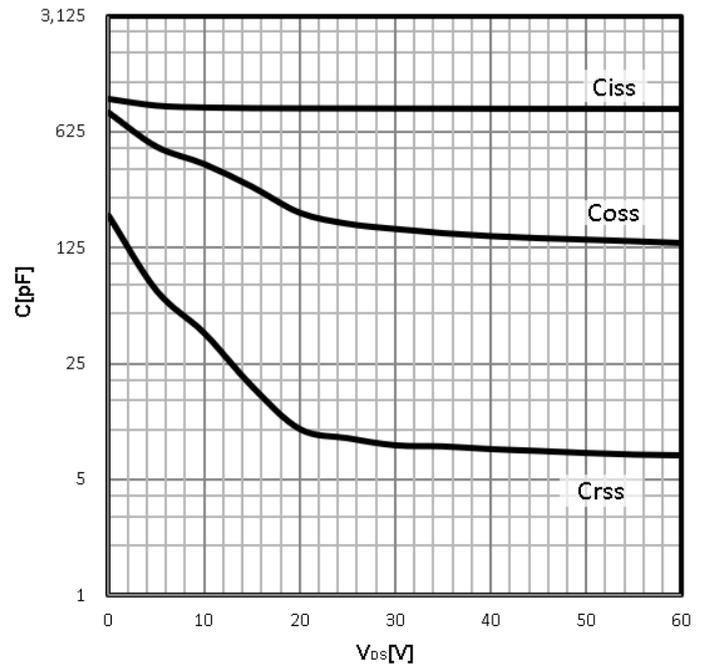
Drain-source breakdown voltage
 $-V_{BR(DSS)}=f(T_j); I_D=-250\mu A$



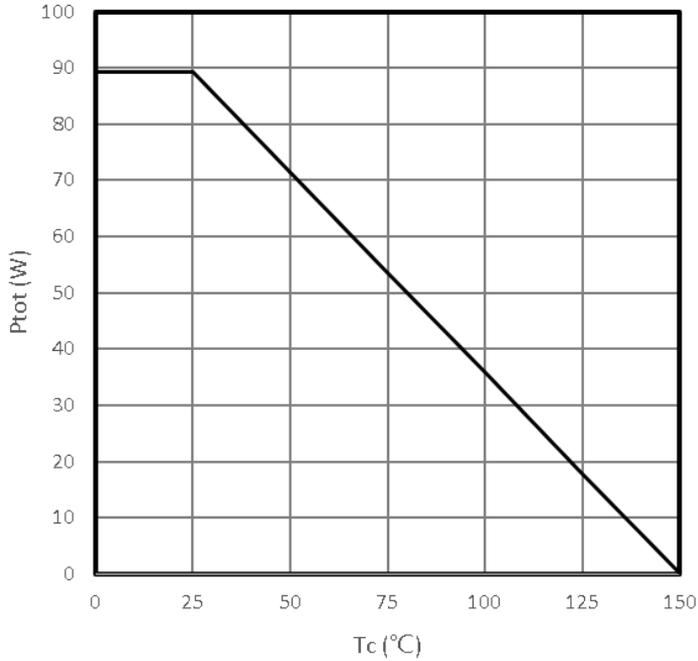
Typ. gate charge
 $-V_{GS}=f(Q_g); I_D=-20A$



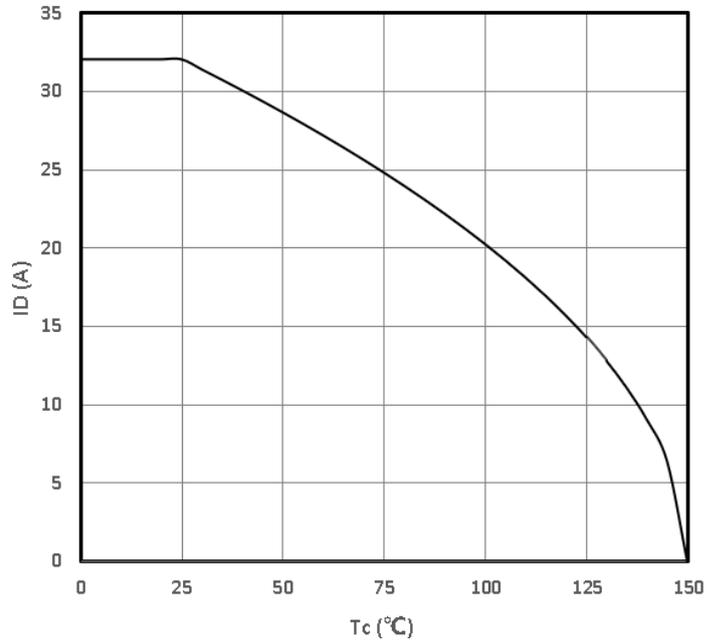
Typ. capacitances
 $C = f(-V_{DS}); V_{GS}=0V; f = 1MHz$



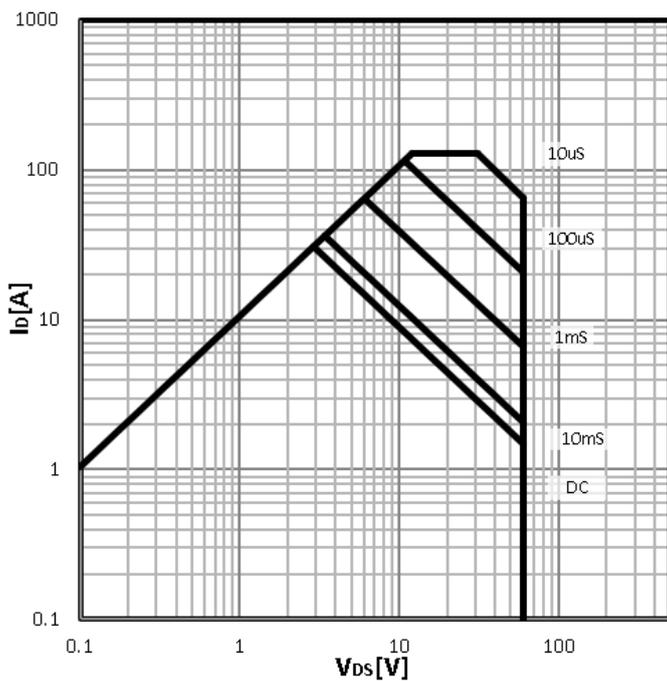
Power Dissipation
 $P_{tot}=f(T_C)$



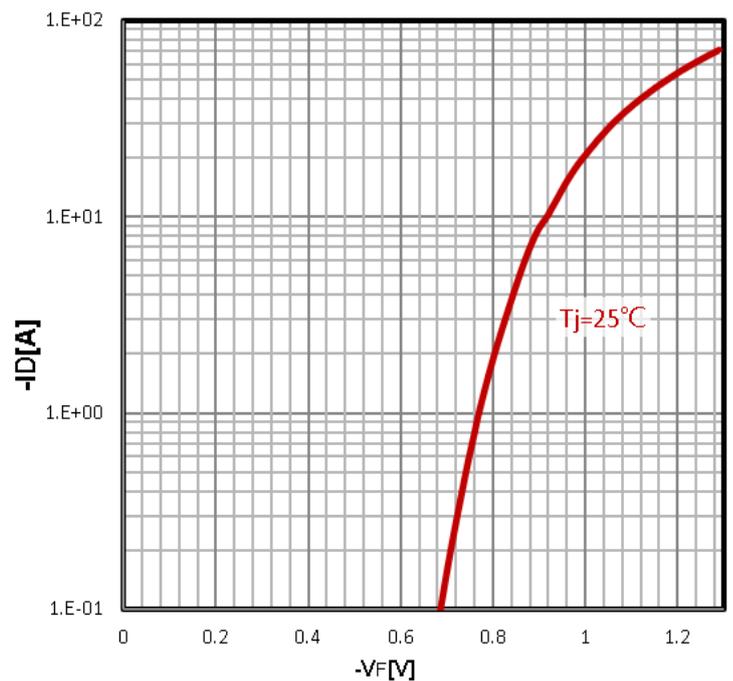
Maximum Drain Current
 $-I_D=f(T_C)$



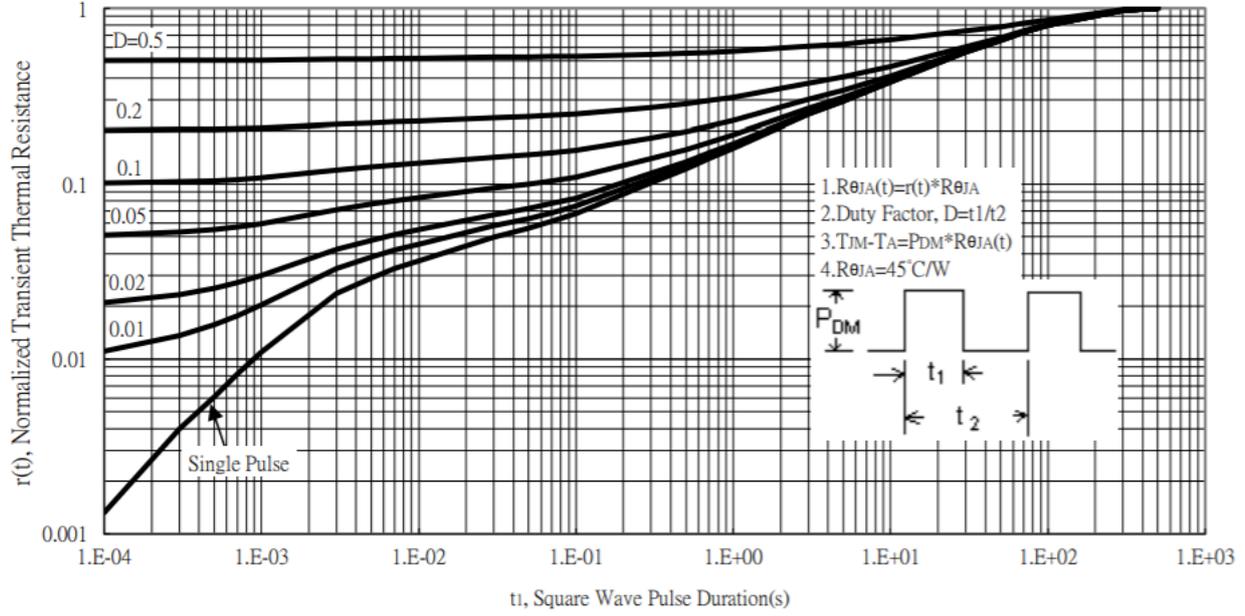
Safe operating area
 $-I_D=f(-V_{DS})$



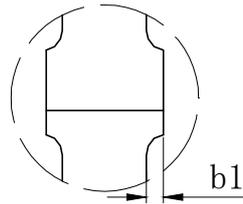
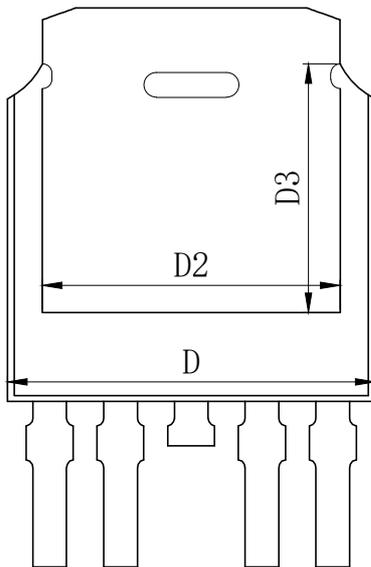
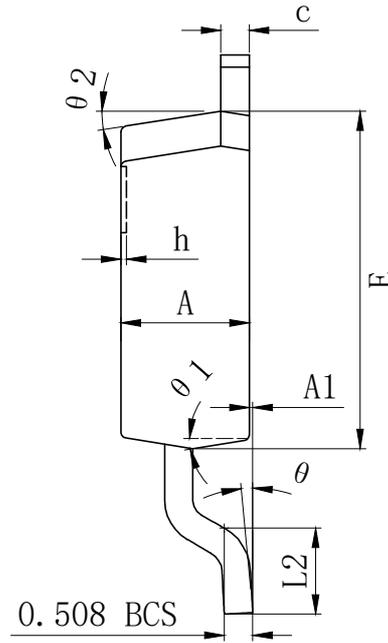
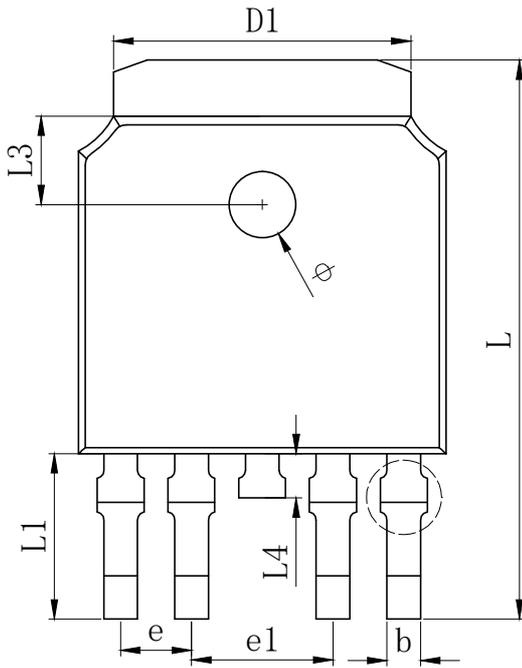
Body Diode Forward Voltage Variation
 $-I_F=f(-V_{DS})$



Max. transient thermal impedance $Z_{thJC} = f(t_p)$



Mechanical Dimensions for TO-252-4L



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	2.200	2.300	2.400
A1	0.000		0.127
b	0.550	0.600	0.650
b1	0.000		0.120
c (电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334 REF		
D2	5.346 REF		
D3	4.490 REF		
E	6.000	6.100	6.200
e	1.270 TYP		
e1	2.540 TYP		
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.988 REF		
L2	1.400	1.550	1.700
L3	1.600 REF		
L4	0.700	0.800	0.900
ϕ	1.100	1.200	1.300
θ	0°		8°
$\theta 1$	9° TYP		
$\theta 2$	9° TYP		